SHARP S21MD4V

S21MD4V

Built-in Zero-cross Circuit, High Noise Resistance Type Phototriac Coupler

- Lead forming type of **S21MD4V** is also available. (**S21MD4W**)
- ** TÜV (DIN-VDE0884) approved type is also available as an option.

■ Features

1. Built-in zero-cross circuit

2. High critical rate of rise of OFF-state voltage $(dV/dt : MIN. 100V/\mu s)$

3. High repetitive peak OFF-state voltage

 $(V_{DRM} : MIN. 600V)$

4. Isolation voltage between input and output

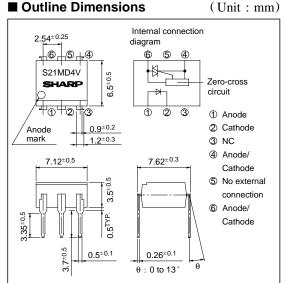
 $V_{\rm iso}:5000 Vrms$

5. UL recognized, file No. E64380 (S21MD4V/S21MD4W)

■ Applications

1. For triggering medium/high power triac

■ Outline Dimensions



■ Absolute Maximum Ratings

 $(Ta = 25^{\circ}C)$

Parameter		Symbol	Rating	Unit	
Input	Forward current	I_{F}	50	mA	
	Reverse voltage	V_R	6	V	
Output	RMS ON-state current	I_T	100	mA_{rms}	
	*1Peak one cycle surge current	I surge	1.2	A	
	Repetitive peak OFF-state voltage	V_{DRM}	600	V	
*2 Isolation voltage		Viso	5 000	V _{rms}	
Operating temperature		T opr	- 30 to + 100	°C	
Storage temperature		T stg	- 55 to +125	°C	
*3 Soldering temperature		T _{sol}	260	°C	

^{*1} Sine wave

^{*2 40} to 60% RH, AC for 1 minute, f = 60HZ

^{*3} For 10 seconds

■ Electro-optical Characteristics

 $(Ta = 25^{\circ}C)$

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Input	Forward voltage	$V_{\rm F}$	$I_F = 20mA$	-	1.2	1.4	V
	Reverse current	I_R	$V_R = 3V$	-	-	10-5	A
Output	Repetitive peak OFF-state current	I_{DRM}	$V_{DRM} = Rated$	-	-	10-6	A
	ON-state voltage	V _T	$I_T = 100 \text{mA}$	-	1.7	2.5	V
	Holding current	I_{H}	$V_D = 6V$	0.1	1	3.5	mA
	Critical rate of rise of OFF-state voltage	dV/dt	$V_{DRM} = 1/\sqrt{2} \text{ Rated}$	100	-	-	$V/\mu s$
	Zero-cross voltage	Vox	Resistance load, I _F = 15mA	-	-	35	V
Transfer character istics	Minimum trigger current	I _{FT}	$V_D = 6V, R_L = 100\Omega$	-	-	15	mA
	Isolation resistance	R ISO	DC500V, 40 to 60% RH	5 x 10 ¹⁰	10^{11}	-	Ω
	Turn-on time	t _{on}	$V_D = 6V, R_L = 100\Omega, I_F = 20mA$	-	20	50	μs

Fig. 1 RMS ON-state Current vs.
Ambient Temperature

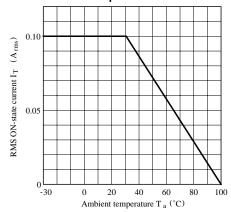


Fig. 3 Forward Current vs. Forward Voltage

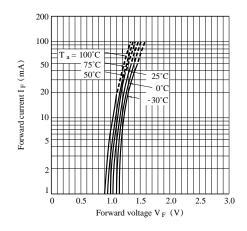


Fig. 2 Forward Current vs.

Ambient Temperature

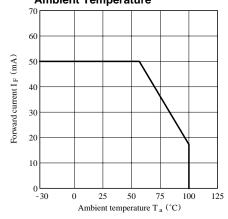


Fig. 4 Minimum Trigger Current vs. Ambient Temperature

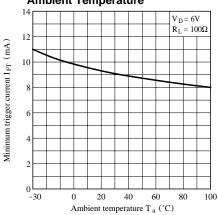


Fig. 5 Relative Repetitive Peak OFF-state Voltage vs. Ambient Temperature

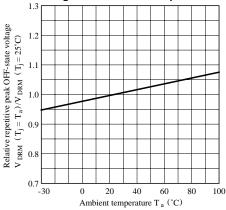


Fig. 7 Holding Current vs.

Ambient Temperature

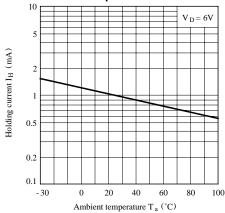


Fig. 9 Repetitive Peak OFF-state Current vs.
Ambient Temperature

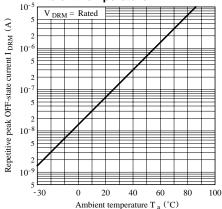


Fig. 6 ON-state Voltage vs.
Ambient Temperature

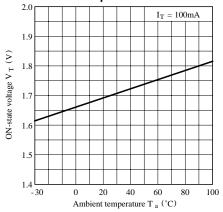


Fig. 8 Repetitive Peak OFF-state Current vs. OFF-state Voltage

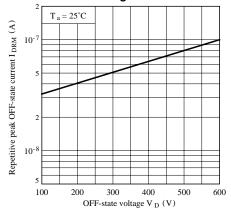


Fig.10 Zero-cross Voltage vs.
Ambient Temperature

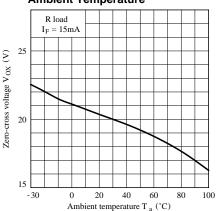
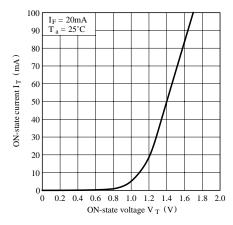
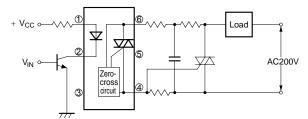


Fig.11 ON-state Current vs. ON-state Voltage



■ Basic Operation Circuit

Medium/High Power Triac Drive Circuit



Note) Please use on condition of the triac for power triggers.

• Please refer to the chapter "Precautions for Use" (Page 78 to 93).

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 - Alarm equipment
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